Abstracts

RF Burnout of Mixer Diodes as Induced Under Controlled Laboratory Conditions and Correlation to Simulated System Performance

G.E. Morris, Y. Anand, V.J. Higgins, C. Cook and G. Hall. "RF Burnout of Mixer Diodes as Induced Under Controlled Laboratory Conditions and Correlation to Simulated System Performance." 1975 MTT-S International Microwave Symposium Digest of Technical Papers 75.1 (1975 [MWSYM]): 182-183.

The mixer diode failure in microwave systems using a TR tube protector depends upon (a) rise time of magnetron, (b) harmonics generated by the magnetron and TR tubes, and (c) spike leakage by the TN tubes. This paper describes the study conducted to establish correlation between mixer diode failure in microwave systems using a TR tube and simulated laboratory set up. Diode failure under microsecond RF pulses and static conditions will also be presented.

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